

ABDUSHKELISHVILI, R. G.

Cand Med Sci - (diss) "Effect of several exogenic factors on hypo- and hyperplastic processes of blood circulation, and problems of inter-relations among these conditions." Tbilisi, 1961. 19 pp; (Tbilisi State Med Inst); 160 copies; price not given; (KL, 7-61 sup, 256)

DESYATCHIKOV, B.A., kand. ekon. nauk; GABZAILOV, G.F., kana. ekon. nauk; KADYROV, Z., nauchn. sotr.; ABDUSHUKUROV, T.; KALIYAKIN, P.V., kand. ekon. nauk; FOKIN, A.I., kand. ekon. nauk; BAKIYEVA, R.A., nauchn. sotr.; IBRAGIMOV, M., nauchn. sotr.; KARDASI, A.A., kand. ekon.nauk; KADANER, E.A.; NIKONOV, F.D., nauchn. sotr.; ANTONETS, G.M.; ARTYKOV, A.A., kand. ekon. nauk; TRUSOV, A.N.; OVCHAROVA, M.A., nauchn. sotr.; TSOY, P., nauchn. sotr.; KALIYAKIN, P.V., kand. ekon. nauk, otv. red.; DZHAMALOV, O.B., doktor ekon. nauk, red.; ARTYKOV, A., kand. ekon. nauk, red.; DESYATCHIKOV, B.A., kand. ekon. nauk, red.; SHARIFKHODZHAYEV, M., kand. ekon. nauk, red.; DESYATNIK, F.M., red.; GOR'KOVAYA, Z.P., tekhn. red.

[Economics of the machinery manufacture of Uzbekistan] Ekonomika mashinostroeniia Uzbekistana. Tashkent, Izd-vo AN Uzb.SSR, 1963. 289 p. (MIRA 16:12)

1. Akademiya nauk Uzbekskoy SSR, Tashkent. Institut ekonomiki. (Uzbekistan--Machinery industry)

ABDUSHUKUROVA, R.U.

Feeding habits of the grass snake in the Tashkent Fish Hatchery during fall period. Zool. zhur. 44 no.3:462-463 '65.

(MIRA 18:8)

1. Institute of Zoology and Parasitology, Academy of Sciences of Uzbek S.S.R., Tashkent.

ABDUSIN, I. P.

37234. ABDUSIN, P. P. i TSNETKOVA, M. A. Rol' struktury kollektorov v reshenii zadach ratsional'noy razrabotki neftyanykh zasobov. Doklad' akad. Na k SSSR, Novaya seriya, T. LXX, No. 5, 1949, s. 663-666. - Bibliogr: 6 nazv.

SO: Letopis' Zhurnal'nykh Statey, Vol. 7, 1949

Handwritten: *Handwritten notes*

MAKSIMYCHEVA, Z.T.; ABDUSLYAMOV, N.

Quantitative determination of potassium in the form of KBF_4 . Zav. lab.
24 no. 4:403-405 '58. (MIRA 11:4)
(Potassium--Analysis) (Potassium fluoborate)

ABDUVAKHIDOV, Kh.

Water balance in virgin Sierozems. Nauch. trudy Tash GU no.204:
156-172 '62. (MIRA 17:9)

ABDUVALIYEV, A.; KHAYRUTDINOVA, M.Kh.; ANDREYEV, A.G.; SULTANOV, A.S.

Thermosetting resin from furfuryl alcohol and furfurole. Uzb.
khim. zhur. no.4:53-57 '58. (MIRA 11:12)

1. Institut khimii AN UzSSR.
(Resins, Synthetic) (Furfuryl alcohol) (Furaldehyde)

SULTANOV, A.S.; ABDUVALIYEV, A.A.

Producing furfuryl alcohol by continuous hydrogenation of furfurole.
Dokl. AN Uz.SSR no.7:19-21 '58. (MIRA 11:10)

1. Institut khimii AN UzSSR. Predstavleno chlenom-korrespondentom
AN UzSSR Kh.U. Usmanovym.
(Furfuryl alcohol) (Furaldehyde) (Hydrogenation)

SULTANOV, A.S.; ABDUVALIYEV, A.A.

Continuous reduction under pressure of furfurole to 2-methyl-
furan. Dokl. AN Uz. SSR no. 12:35-37 '58. (MIRA 12:1)

1. Institut khimii AN UzSSR. Predstavleno chlenom-korrespondentom
AN UzSSR Kh. U. Usmanovym.
(Furaldehyde) (Furan)

ABDUVALIYEV, A.A.; KHAYRUTDIYNOVA, M.Kh.; ANDREYEV, A.G.; SULTANOV, A.S.

Method for the production of glue for repairs of wires with
polyvinyl chloride insulation. Uzb. khim. zhur. no.3:72: '59.
(MIRA 12:9)

(Electric wire, Insulated--Maintenance and repair)

KORSHAK, V.V.; SULTANOV, A.S.; ABDUVALIYEV, A.A.

Polymerization of furan and sylvan with the aid of ionic
catalysts. *Usb.khim.zhur.* no.4:39-47 '59. (MIRA 13:1)

1. Institut khimii polimerov AN UzSSR i Institut eksperimental'-
noy optiki i spektroskopii AN SSSR.
(Furan) (Catalysts) (Polymerization)

SULTANOV, A.S.; ABDUVALIYEV, A.

Polymerization of sylvan and furan. Dokl. AN Uz. SSR no. 6:24-26
'59. (MIRA 12:9)

1. Institut khimii AN UzSSR. Predstavleno chlenom korrespondentom
AN UzSSR Kh. U. Usmanovym.
(Polymers and polymerization)

ABDUVALIYEV, A. A., Cand Chem Sci -- (diss) "Obtaining some film-forming polymers on a basis of furfural." Tashkent, 1960. 15 pp with graphs; (Academy of Sciences Uzbek SSR, Inst of the Chemistry of Polymers); 175 copies; price not given; (KL, 25-60, 127)

KHAYDAROV, Kh.F.; SULTANOV, A.S.; ARMUVALIYEV, A.A.

Polymerization of styrene in the presence of complex ionic catalysts consisting of antimony, cadmium, and aluminum chlorides and organosilicon compounds. Khim. i fiz.-khim. prirod. i sint. polim. no.12131-137 '62 (MIRA 18:1)

Polymerization of styrene in solution. Ibid. 2138-242

ISRAILOV, D.; ABDUVALIYEV, A.A.; BRONOVITSKIY, V. Ye.; SULTANOV, A.S.

Processing of polytetrafluoroethylene into films by mixing
with polysilvan. Khim. i fiz.-khim. prirod. i sint. polim. no.1:
215-219 '62 (MIRA 18:1)

S/081/62/000/015/036/038
B171/B101

AUTHORS: Khaydarov, Kh. F., Abduvaliyev, A. A., Sultanov, A. S.

TITLE: Investigation of the polymerization of sylvan in the presence of organo-titanium-silicon halide ionic catalysts

PERIODICAL: Referativnyy zhurnal. Khimiya, no. 15, 1962, 632, abstract 15R35 (Sb. "Vopr. izpol'zovaniya mineral'n. i rastit syr'ya Sredn. Azii." Tashkent, AN UzSSR, 1961, 120-132)

TEXT: The reaction of the polymerization of sylvan under the action of complex catalysts: $Ti[CH_3Si]_2Cl_{10}$, $Ti[(CH_3)_2Si]_2Cl_8$, $Ti[(CH_3)_3Si]_2Cl_6$ and $Ti[C_6H_5Si]_2Cl_{10}$ has been investigated. The reaction was carried on for 5 hours at $50^{\circ}C$ and the amount of the catalyst used represented 0.5-4% mole per mole sylvan. The yield of the polymer increases with the decrease of the number of methyl groups in the catalyst. The molecular weight of polysylvan ranges from 1500 to 2000. Polysylvans thus prepared may be used in the paint and varnish industry. [Abstracter's note: Complete translation.]

Card 1/1

ABDUVALIYEV, A.A.; BODNYA, M.D.; BARANOVSKAYA, G.M.; OBNOSOVA, A.D.;
ISRAILOV, D.

Continuous method of sylvan polymerization in the solvent medium.
Lakokras.mat.1 ikh prim. no.6:27-29 '62. (MIRA 16:1)
(Sylvan)

ABDUVALIYEV, A.A.; BODNYA, M.D.; BARANOVSKAYA, G.M.; OBNOSOVA, A.D.

Investigating the film forming properties of polysilvan modified with
PF-6 alkyd resins. Lakokras.mat. i ikh prim. no.2:17-18 '63.

(MIRA 16:4)

(Furan)

(Resins, Synthetic)

L 14947-63

EWP(j)/EWT(m)/BDS ASD Pc-4 RM

ACCESSION NR: AP3003791

S/0190/63/005/007/1012/1015

AUTHORS: Khaydarov, Kh. F.; Abduvaliyev, A. A.; Sultanov, A. S.

TITLE: Chemical structure of polysylvan η

SOURCE: Vy*sokomolekulyarny*ye soyedineniya, v. 5, no. 7, 1963, 1012-1015

TOPIC TAGS: sylvan, polysylvan, furan, polymerization, ozonization

ABSTRACT: To find out the proper structure of polysylvan, two grams of the latter were dissolved in 40 ml of chloroform and subjected to ozonization at 0C by passing into it oxygen containing 2.5-3.5% ozone at a rate of 50-60 ml/min. The ozonization was discontinued when the fluid turned blue, and the chloroform was distilled out. The ozonized product was decomposed by treatment at 80-90C with 30 ml of hydrogen peroxide, resulting in a turbulent evolution of carbon dioxide and leaving a brittle spongy mass. The latter was subjected to analysis for carboxyl, hydroxyl, and acetyl groups by standard chemical procedures as well as by infrared spectroscopy. While the test for acetyl groups proved negative, the acidity number was estimated as 23.1 and the percentage of hydroxyl groups as 17.1, from which it was determined that polymerization of sylvan takes place at the C=C bonds of the furan ring with the methylated carbon atom. The infrared spectra were taken by Yu. T. Tashpulatov and Yu. P. Putnev at the analytical laboratory of the Institute. Orig. Card 1/77

Association: Inst. of Polymer Chemistry, Academy of Sciences, Uzbek SSR

ABDUVALIYEV, A.A.; KHAYDAROV, Kh.F.; SAGDULLAYEVA, P.; OBNOSOVA, A.D.

Lacquers based on urea-formaldehyde resins modified with furfuryl alcohol. Lakokras.mat. 1 ikh prim. no.2:67-69 '64. (MIRA 17:4)

ABDUVALIYEV, A.A.; KHAYDAROV, Kh.F.; SULTANOV, A.S.; SIGOV, V.V.;
DORONIN, N.L.; TARASOVA, A.G.

Production of polysylvan from the wood-chemical sylvan. Gidroliz.
i lesokhim.prom. 17 no.2:22-23 '64. (MIRA 17:4)

1. Institut khimii polimerov AN UzbSSR (for Abduvaliyev,
Khaydarov, Sultanov). 2. Ashinskiy lesokhimicheskiy kombinat
(for Sigov, Doronin, Tarasova).

ACCESSION NR: AT4040809

S/3099/62/000/001/0215/0219

AUTHOR: Israilov, D., Abduvaliyev, A. A., Bronovitskiy, V. Ye., Sultanov, A. S.

TITLE: Conversion of polytetrafluoroethylene into films by mixing with polysylvan

SOURCE: AN UzSSR. Institut khimii polimerov. Fizika i khimiya prirodny*kh i sinteticheskikh polimerov, no. 1, 1962, 215-219

TOPIC TAGS: teflon, polytetrafluoroethylene, polysylvan, polymer film, teflon film, polymer mechanical property, dimethyldichlorosilane, polymer electrical resistivity

ABSTRACT: Polysylvan, obtained by the polymerization of sylvan in the presence of $ZnCl_2$ and dimethyldichlorosilane in N_2 at 50C, was then used for the preparation of teflon films by two methods: (1) Mixing of powdered polytetrafluoroethylene with polysylvan in ratios of 1:1 to 1:5, and heating in reactors at 280-300C; however, homogeneous products could not be obtained at any intervals of temperature and polymer ratios. (2) Mixing various proportions of the polymers in rollers at a roller friction of 1:1.2 and temperatures of 30-80C. In both cases, films of various thickness with different physico-mechanical indices were

Card

1/3

ACCESSION NR: AT4040809

obtained. The best conditions were rolling at 50-60C for 40 minutes. Part of the films were baked in presses at 280-300C and the rest were extracted with acetone to remove the excess polysilvan and then baked at 300C. When 1:1 mixtures of polytetrafluoroethylene and polysilvan were rolled at 50-60C for 10, 20, 40 and 60 minutes, the rupture strength of the films obtained was 85, 130, 162 and 105 kg/cm², respectively. To study the effect of the presence of silicon in the polymer on the blending of polytetrafluoroethylene, experiments were carried out with polysilvan containing silicon on one or both ends of the chain. The rupture strength of these films was 51 and 170 kg/cm², respectively. The authors also studied the electrical resistance of the films, with or without removal of excess polysilvan. The results showed a decrease in electrical resistivity with increasing temperature (20-150C), and an increase after extraction with acetone. When films containing excess polysilvan were baked on an hydraulic press with a pressure of 20 kg/cm² at 280-300C, dark colored films were obtained with holes from the leakage of the excess polysilvan. To eliminate this problem, the quantity of bound and free polysilvan in the film at a 1:1 ratio of polytetrafluoroethylene to polysilvan was studied. An average of 18% of the original polysilvan remained in the film after washing. Films from which the excess polysilvan had been removed were highly

2/3

Card

ACCESSION NR: AT4040809

resistant to all solvents, including concentrated nitric acid. Orig. art. has: 2 tables.

ASSOCIATION: Institut khimii polimerov AN Uz SSR (Institute of Polymer Chemistry,
AN Uz SSR)

SUBMITTED: 00

ENCL: 00

SUB CODE: OC, MT

NO REF SOV: 004

OTHER: 001

Card 3/3

"APPROVED FOR RELEASE: 04/03/2001

CIA-RDP86-00513R000100120013-3

APPROVED FOR RELEASE: 04/03/2001

CIA-RDP86-00513R000100120013-3"

SECRET CONFIDENTIAL TOP SECRET

ACCESSION NR. AP5601139

L 27015-65

ACCESSION NR AP5001139

Polymerization of styrene in the presence of 2 mole-% sulfuric acid etherate (C₂H₅O)₂S₂O₈ and in the presence of 5 mole-% sulfuric acid. The products are formed on drying films and are used as a catalyst.

ASSOCIATION - Institut khimii polimerov AN UZSSR (Institute of Polymer Chemistry, Academy of Sciences of the Uzbek SSR)

BM: 1. ETC. (MATERIALS)

EN

1962

SECRET SOV. COP

OTHER

1962 2

1. AUTHOR: Abduvaliyev, A. (Aspirant)

AUTHOR: Abduvaliyev, A. (Aspirant)

TITLE: Characteristics of some indices of protein metabolism in brucellosis patients before the disease

SOURCE: Meditsinskiy zhurnal Uzbekistana, no. 11, 1964, 29-30

Card 1/1

L 56571-65

ACCESSION NR: AP5018601

... was high at first while the A/C ratio was low. The
 ...
 ... SOME DIFFERENCES ...
 ... AND THE A/C RATIO ...
 ...

NE REF SOV: 000

OTHER: 000

SUB CODE: LS

JPRS

Card 2/2

"APPROVED FOR RELEASE: 04/03/2001

CIA-RDP86-00513R000100120013-3

APPROVED FOR RELEASE: 04/03/2001

CIA-RDP86-00513R000100120013-3"

ORIG. ATT. HAS: 2 TABLES AND 3 FORMULAS.

MADZHIDOV, A.; ABDOVALIYEV, A.; SULTANOV, A.S.

Production of 2,5-dimethylolfulan. Uzb.khim.zhur. 9 no.1:72-75
'65. (MIRA 18:6)

1. Institut ispol'zovaniya topliva Gosudarstvennogo neftekhimicheskogo
komiteta pri Gosplane SSSR.

KHAYDAROV, Kh.F.; ABDUVALIYEV, A.A.; SULTANOV, A.S.

Polymerization of silvan on complex ionic catalysts and the use of polysilvan as a film-forming agent. Uzb.khim.zhur. 8 no.4:65-70 '64. (MIRA 18:12)

1. Institut khimii polimerov AN UzSSR. Submitted May 4, 1962.

ABDUVALIYEV, A.A.; ISMATOV, N.Kh.; BARANOVSKAYA, G.M.

Copolymerization of silvan and tung oil. Uzb. khim. zhur. 9
no.5:48-52 '65. (MIRA 18:12)

1. NIIKhTTS. Submitted Feb. 20, 1964.

L 25819-66 EWT(a)/EWP(j)/T IJP(c) WH/RM

ACC NR: AP6008691

(A)

SOURCE CODE: UR/0291/65/0v0/005/0048/0052

AUTHOR: Abduvaliyev, A. A.; Ismatov, N. Kh.; Baranovskaya, G. M.ORG: NIIKhITSTITLE: Copolymerization of sylvan and tung oil¹⁵SOURCE: Uzbekskiy khimicheskiy zhurnal, no. 5, 1965, 48-52TOPIC TAGS: copolymerization, sylvan, tung oil, *ionic catalyst*

ABSTRACT: The copolymerization of sylvan and tung oil in the presence of ionic catalysts was carried out at 50°C in an inert gas atmosphere with constant stirring. The catalysts, $ZnCl_2$, $(CH_3)_xSiCl_y$, and sulfuric acid etherate, were found to be completely suitable for obtaining high yields of sylvan-tung oil copolymers. Lacquer films on glass and steel substrates were prepared from the solutions, and the physicomuchanical properties of the copolymer films were measured. As the sylvan content of the copolymer increases, the drying rate of the film, its hardness, luster, and water resistance increase. The optimum ratio of sylvan to tung oil was found to range from 80:20 to 50:50. The films adhere well to metal and wood. Infrared spectra indicate that the copolymerization of sylvan and tung oil in the presence of ionic catalysts forms a substance with a higher molecular weight and a lower specific functionality than those of the initial oil. This causes a decrease in the gelation rate of the copolymer as its sylvan content increases. Orig. art. has: 2 figures, 2 tables.

SUB CODE: 07/

SUBM DATE: 20Mar64/

ORIG REF: 002/

OTH REF: 000

Card 1/1 *fv*

COUNTRY : USSR
CATEGORY : Soil Science. Soil Genesis and Geography. J
ABS. JOUR. : RZhBiol., No. 3 1959, No. 10662
AUTHOR : Abdiyev, M. R.
UNIT : Academy of Sciences, Azerbaijan SSR
TITLE : Dynamics of the Salification of Soils in Eastern Shirvan'.
ORIG. PUB. : Tr. 4-y nauchn. konferentsii aspirantov AN AzerbSSR.
Baku, 1955, 69-97
ABSTRACT : The saline condition of the following soils of Eastern Shirvan' is described: the dark brown after-forest (chernozem-like) soil, dark chestnut, meadow-stercosom covered with steppe, meadow-bog and meadow solonchak soils.

REF: 1/1

ABDUYEV, M.R.

Moisture regime of soils in the eastern part of the Shirvan Steppe.
Trudy Inst.pochv.i agrokhim.AN Azerb.SSR 7:215-223 '55. (MLRA 9:12)
(Shirvan Steppe--Soil moisture)

ABDUYEV, H. R.

ABDUYEV, H. R.: "The water-salt dynamics of soils of the eastern portion of Shirvan Steppe." Published by the Acad Sci Azerbaydzhan SSR. Min Higher Education USSR. Armenian Agricultural Inst. Baku, 1956. (Dissertations for the Degree of Doctor in Agricultural Sciences).

SO: Knizhnays Letopis' No. 22, 1956

ABDUYEV, M.R.

Geomorphology of the eastern part of Shirvan Steppe. Izv.
AN Azerb.SSR no.4:59-68 Ap '56. (MLRA 9:10)

(Shirvan Steppe--Geology, Structural)

USSR/Cultivated Plants - Fruits. Berries.

M-6

Abs Jour : Ref Zhur - Biol., No 7, 1958, 29988

Author : Abduev, M.

Inst :

Title : From an Attempt to Reclaim Salt Lands for Gardens and Vineyards.

Orig Pub : Sots. s. kh. Azerbaydzhan, 1956, No 10, 19-21

Abstract : Description is given of the salt land conditions of the soils occupied by gardens and vineyards in the sovkhos near the city of Mingechaur in Azerbaydhan. The agro-techny is indicated which is needed to increase the salt resistance of the plantings.

Card 1/1

- 1 -

ABDUYEV, M.R.

Soil moisture cycle and conditions for the development of agricultural crops in the eastern part of the Shirvan Steppe [in Azerbaijani with summary in Russian]. Izv. AN Azerb. SSR no. 93-110 1957. (MIRA 10:8)
(Shirvan Steppe--Crops and soils)
(Soil moisture)

~~ABDUYEV, M.R.~~

Salinization conditions and types of saline soils in the eastern
part of the Shirvan Steppe. Trudy Inst. pochv. i agrokhim. AN
Azerb. SSR 8:47-82 '58. (MIRA 12:10)
(Kura Lowland--Alkali lands)

ABDUYEV, M.R.

Specific nature of the deluvial type of soil salinity in the Kura-
Aras Lowland. Izv.AN Azerb.SSR,Ser.biol. i sel'khoz. nauk no.1:81-94
' 59. (MIRA 12:1)

(Kura Lowland--Alkali lands)

ABDUYEV, M.R.

Chemical and geographical characteristics of soils with a talus-type salinity in the Siazan'-Sungait Massif. Izv.AN Azerb.SSR.Ser.biol.i med.nauk 3:57-64 '61.

(Siazan' region—Saline and alkali soils)
(Sungait region—Saline and alkali soils)

(MIRA 14:7)

ABDUYEV, M.R.

Solonetz soils formed from talus deposits and conditions
governing their improvement in Azerbaijan. Izv. AN Azerb.
SSR Ser. biol i med. nauk no.8:77-85'61. (MIRA 16:8)
(AZERBAIJAN-SOLONETZ SOILS)
(RECLAMATION OF LAND)

ABDUYEV, M.R.

Significance of diffusion in the migration of salts. Izv.AN
Azerb.SSR.Ser.biol.i med.nauk no.6:49-57 '62. (MIRA 15:12)
(MINERALS IN SOIL) (DIFFUSION)

ABDUYEV, M.R.

Soil conditions and the development of the root system of saltworts.
Izv. AN Azerb. SSR. Ser. biol. i med. nauk no.2:69-78 '63.
(MIRA 17:5)

ABDUYEV, M.R.

Amounts of vegetative bulk under the conditions found in
the western Caspian Lowland of Azerbaijan. Dokl. AN Azerb.
SSR 19 no.5:31-34 '63. (MIRA 17:2)

1. Institut pochvovedeniya i agrokhemii AN AzSSR. Pred-
stavleno akademikom AN AzSSR G.A. Aliyevym.

ABDUYEV, M.R.

Rect. system of worms in the lowland of Azerbaijan. Tr. AN
Azerb. SSR. Ser. biol. i med. nauk no. 5:65-74. '63.

(MIRA 17:5)

BUYEV, M.R.

Types of the salt profiles of soils with the diluvial form of salinity in the lowlands of Azerbaijan. Izv. AN Azerb. SSR. Ser. biol. nauk no.2:73-80 '64.

(MIRA 17:10)

ABDIYEV, M.R.

Formation and evaluation of surface runoff in the piedmont plains
of Azerbaijan. Izv. AN Azerb. SSR. Ser. Biol. Nauk no. 2: 5-74 165.
(1978 18:7)

ABDUYEVSKAYA, K. A., Cand Chem Sci -- (diss) "Investigation of complex fluorides and oxalates of germanium." Moscow, 1960. 7 pp; (Academy of Sciences USSR, Inst of General and Inorganic Chemistry im N. S. Kurnakov); 150 copies; price not given; (KL, 17-60, 141)

ABDUZHABAROV, MA.

Nuriddin's ice cave. Priroda 52 no.4:115-116 '63.

(MIRA 16:4)

1. Samarkandskiy gosudarstvennyy universitet im. Alishera Navoi.
(Zeravshan Range—Ice caves)

ABDUZHABBAROVA, Kh.Yu.

Stratigraphy of Silurian sediments in the Shurab region. Vop.
geol. Uzb. no.3:38-41 '62. (MIRA 1686)

(Shur-Ob —Paleontology, Stratigraphic)

SIMAKOV, V. N.; ABDUZHALALOV, A.

Comparative study of the effectiveness of soil claying in the
"dry" and "wet" sands of Leningrad Province. Vest. LGU. 16 no.21:
121-130 '61. (MIRA 14:11)
(Leningrad Province—Soil fertility)
(Clay)

ABDUZHAMILOV, Sh.; AZIMOV, S.A.; CHERNOVA, L.P.; CHERNOV, G.M.; CHUDAKOV, V.M.

Azimuthal angular distribution of shower particles produced
by cosmic ray particles in a photographic emulsion. Zhur. eksp.
i teor. fiz. 45 no.3:407-414 S '63. (MIRA 16:10)

1. Institut yadernoy fiziki AN Uzbekskoy SSR.
(Photography, Particle track)
(Cosmic rays)

ACCESSION NR: AP4042364

S/0056/64/047/001/0024/0029

AUTHORS: Abduzhamilov, Sh.; Azimov, S. A.; Chernova, L. P.; Chernov, G. M.; Chudakov, V. M.

TITLE: Angular distributions of secondary particles in pN collisions at 24 BeV energy

SOURCE: Zh. eksper. i teor. fiz., v. 47, no. 1, 1964, 24-29

TOPIC TAGS: pion scattering, angular distribution, nucleon scattering, dispersion analysis, nuclear emulsion

ABSTRACT: The research was undertaken because asymmetric emission of particles was observed in nucleon-nucleon collisions at energies of several hundred BeV (V. V. Guseva et al., Izv. AN SSSR, Ser. fiz., v. 26, 549, 1962. N. A. Dobrotin et al., Nuclear physics v. 35, 152, 1962). The statistical method of dispersion analysis (the F test) is used to check the hypothesis of independent secondary-particle

1/3

ACCESSION NR: AP4042364

emission angles in inelastic pN interactions involving primary protons of equal energy E and equal numbers n of charged secondary particles. The experimental values of F for pN interactions at 24 BeV and for 4--9 charged secondary particles conflict with this hypothesis and indicate nonuniformity of the angular distributions in the laboratory system. This nonuniformity cannot be accounted for by momentum conservation in knock-on collisions and is associated with the particle production mechanism in peripheral interactions. The efficiency of the F -test for determining nonuniform angular distribution in the laboratory system was checked by investigating the random stars obtained from a somewhat different model of NN interactions at 300 BeV, by obtaining the spectrum of meson cloud velocities in the center of mass system and the secondary-particle energy spectrum in the rest system of the meson cloud. An accelerated on-track scanning of plates bombarded with 24-BeV protons in the CERN accelerator has shown that for the stars observed in the emulsion the most values of F exceed unity, meaning that the emission angles of the secondary particles are not independent at least for some

2/3

ACCESSION NR: AP4042364

values of n . The nonuniformity of the angular distributions is similar to the asymmetric c.m.s. particle emission observed in NN collisions at $\sim 10^{11}$ eV. The peripheral interactions at E-24 BeV remains dominant up to a multiplicity $n = 9$. "The authors are grateful to W. O. Lock for collaborating in the acquisition of the photographic plates exposed in the CERN accelerator." Orig. art. has: 2 figures and 19 formulas.

ASSOCIATION: Institut yadernoy fiziki Akademii nauk Uzbekskoy SSR
(Institute of Nuclear Physics, Academy of Sciences, Uzbek SSR)

SUBMITTED: 23Jan64

ENCL: 00

SUB CODE: NP

NR REF SOV: 003

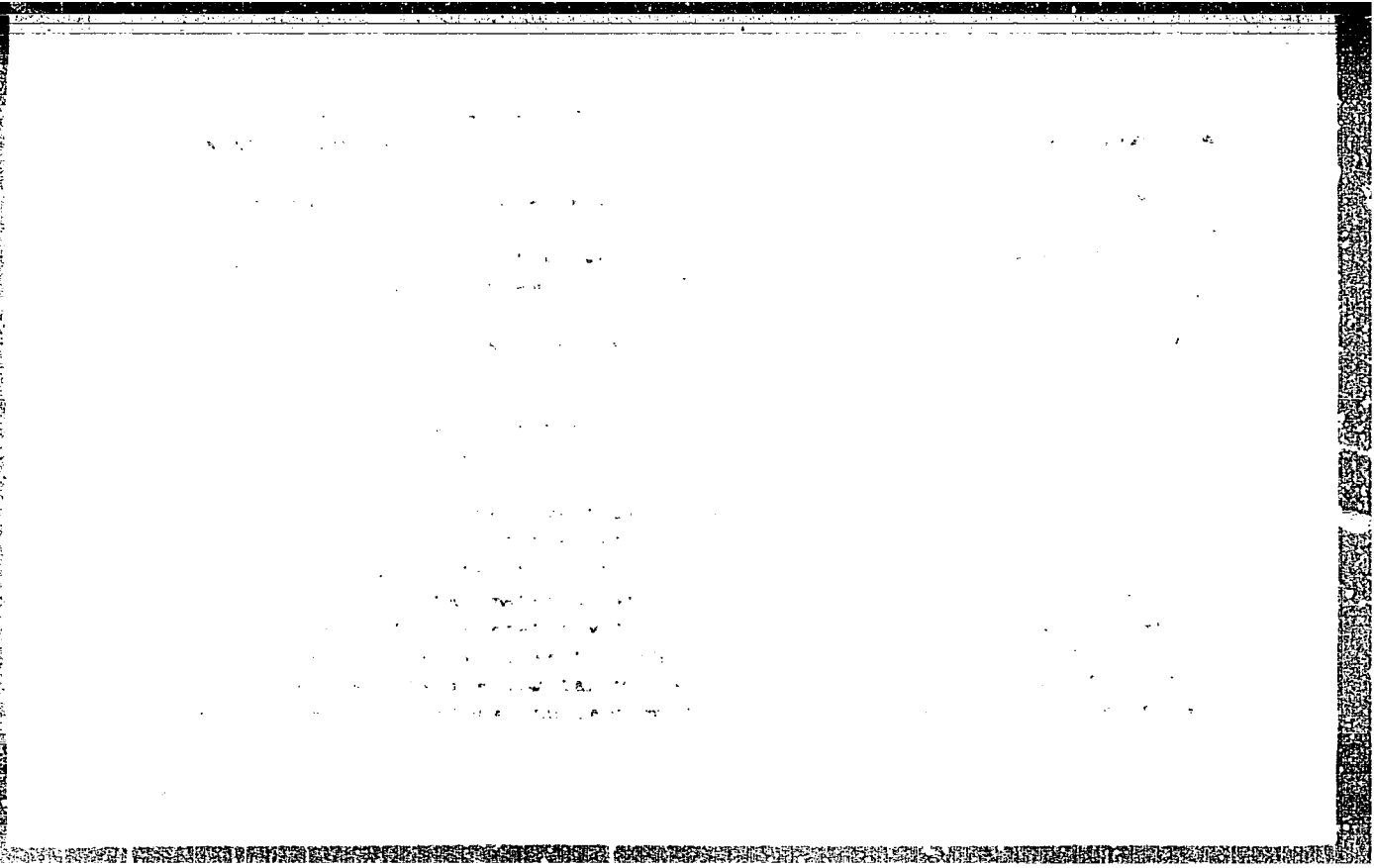
OTHER: 001

3/3

ABDUZHAMILOV, Sh.; AZIMOV, S.A.; CHERNOVA, L.P.; CHERNOV, G.M.;
CHUDAKOV, V.M.

Angular distributions of secondary particles in pN-
collisions at an energy of 24 Bev. Zhur. eksp. i teor.
fiz. 47 no.1:24-29 J1 '64. (MIRA 17:9)

1. Institut yadernoy fiziki AN Uzbekskoy SSR.



ASSOCIATION: Institut yadernoy fiziki AN UzSSR (Institute of Nuclear Physics, AN
UzSSR)

SUBJECT: 2706164

ENCLOSURE

FILE CODE: NP

L 45314-66 SWT(m)/T

ACC NR: AP6023083 (AN) SOURCE CODE: UR/0367/66/003/004/0657/0662

AUTHOR: Abduzhamilov, Sh. ; Azimov, S. A. ; Chernova, L. P. ; Chernov, G. M. ; Chudakov, V. M.

ORG: Institute of Nuclear Physics, Academy of Sciences, Uzbek SSR (Institut yadernoy fiziki akademii nauk uzbekskoy SSR)

TITLE: Coherent ¹⁹interaction of high-energy protons with complex nuclei

SOURCE: Yadernaya fizika, v. 3, no. 4, 1966, 657-662

TOPIC TAGS: proton, high energy protin, photoemulsion, nucleon, particle interaction, proton interaction, inelastic interaction

ABSTRACT: The authors use a method proposed in a previous work [Sh. Abduzhamilov, S. A. Azimov, L. P. Chernova, G. M. Chernov, V. M. Chudakov ZhETF, 47, 24, 1964] to find and analyze in detail the differences between the angular distributions of secondary particles in showers formed by high-energy protons and satisfying the necessary selection criteria for pp and pn collisions in

Cord 1/2

L 45311-66

ACC NR: AP6023083

photoemulsions. These differences are easily explained by the inclusion of coherent interactions. The method of research is also explained in detail. Experimental data are presented and discussed. The results are discussed of processing the showers formed in photoemulsions by protons with 24 gev and satisfying the necessary criteria of selection of pn collisions. Measurements have been made previously by the authors, the number of particles being $n \geq 4$. The differences found indicate the possible existence of coherent interactions of protons with complex nuclei among the showers with three and four secondary charged particles at 10 and 24 gev. The authors also used measurements made at the Laboratory of High Energies of the Joint Nuclear Research Institute (Olyal) during investigation of inelastic pn interactions of protons with an energy of 10 gev with free and quasi-free nucleons of the photoemulsion. The authors are grateful to V. I. Veksler for permission to use the experimental data obtained at the LVE Olyal, and to M. I. Podgoretskiy for discussions of the work. Orig. art. has: 2 figures, 15 formulas, and 1 table. [GC]

SUB CODE: 20/ SUBM DATE: 12Mar65/ ORIG REF: 002/ OTH REF: 001/

Card 2/2 mjs

ABDIAZIMOV, Kh.A.; SMIRNOVA, L.S.; YUNUSOV, S.Yu.

Interconversion of the alkaloids hippastrine, ungerine and unsevine. Dokl. AN Uz. SSR 21 no.8:24-27 '64.

(MIRA 19:1)

1. Institut khimii rastitel'nykh veshchestv AN UzSSR.

ABDULAYEV, D.M.

Some results of the study of the distribution of atherosclerosis
among different population groups in the Azerbaijan S.S.R.
Azerb. med. zhur. 42 no. 7:3-8 J1 '65 (MIRA 19:1)

ATROSHCHENKO, V.I.; SHCHEDRINSKAYA, Z.M.; GAVRYA, N.A.; Priznani uchestiya:
AYRAPETYAN, M.T.; ABDULAYEVA, G.A.; TIMOKHINA, M.S.; KUD', A.A.

Catalysts for oxidation processes of natural gas to form
formaldehyde and methanol. Zhur.prikl.khim. 38 no.3:643-
649 Mr '65. (MIRA 18:11)

1. Submitted Febr. 27, 1963.

ABDYKHALYKOVA, F.D.; KATSMAN, Ya.N.

Treatment of dermatomycosis in Semipalatinsk Province. Zdrav. Kazakh.
21 no.5:9-10 '61. (MIRA 15:2)
(SEMPALATINSK PROVINCE...DERMATOMYCOSIS)

ABDYLAYEV, A.A.

Thermal conditions of semiconductor diodes in a.c.circuits. Izv.vys.
ucheb.zav.;prib. 7 no.5:144-150 '64. (MIRA 17:12)

1. Azerbaydzhanskoy nauchno-issledovatel'skiy institut elektro-
tekhnicheskoy promyshlennosti. Rekomendovano mezhvuzovskoy kon'eren-
tsiyey po teplovyim rezhimam radioelektronnykh ustroystv (detaley i
apparatov).

TURUSBĀKOV, M.; ABDYLDAEV, A., red.; ANOKHINA, M.G., tekhn.red.

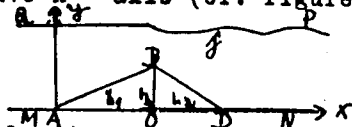
[Dictionary of physics terminology] Fizikalyk terminderdin
sozdugu; doolboor. Slovar' fizicheskikh terminov; proekt.
Frunze, Akad.nauk Kirgizskoi SSR. Terminologicheskaja
komissia, 1960. 190 p. (MIRA 13:7)
(Physics--Dictionaries)
(Russian language--Dictionaries--Kirghiz)

86174

16-7600

S/140/60/000/005/001/021
C111/C222AUTHOR: Abdylayev, A.A.TITLE: The Theory of Flow in a Channel With a Low Triangular Hindrance
at the GroundPERIODICAL: Izvestiya vysshikh uchebnykh zavedeniy. Matematika, 1960,
No. 5, pp. 3 - 11TEXT: In the $z = x + iy$ -plane let OX form the ground of the channel, let QP be the free surface, ABD be the hindrance. Let the fluid flow in the direction of the positive x -axis (cf. figure)

Fig. 1



For $x = -\infty$ let the velocity c and the depth h be known. For subcritical velocities, at the right side of the hindrance there appear waves the amplitude of which depends on the hindrance. By usual arrangements (conformal mapping) the author determines the field of velocities and the free surface with a consideration of the small terms of first order, and the

Card 1/5

86174

The Theory of Flow in a Channel With a Low
Triangular Hindrance at the Ground

S/140/60/000/005/001/021
C111/C222

wave resistance with a consideration of the terms of second order. Under consideration of the fact that the height h_1 of the hindrance is very small, for the mapping into the plane of the complex potential $w = \varphi + i \psi$ the author uses (according to Wien (Ref. 1)) the formula

$$(2) \quad \frac{dz}{dw} = \frac{1}{\sigma} (w-a_1)^{\alpha_1-1} (w-a_2)^{\alpha_2-1} (w-a_3)^{\alpha_3-1} [1 + \epsilon \Omega(w)] ,$$

where a_1, a_2, a_3 are points of the φ -axis corresponding to A, B and D, $\alpha_1 + \alpha_2 + \alpha_3 = 3$, $\epsilon = \frac{h_1}{h}$ and $\Omega(w)$ is given by the boundary con-

ditions

$$(3) \quad \text{Im } \Omega(w) = 0 \text{ for } \psi = 0, -\infty \leq \varphi \leq \infty .$$

$$(4) \quad \Omega(w) = 0 \text{ for } \varphi = -\infty, 0 \leq \psi \leq a$$

and

$$(5) \quad \text{Re} \left\{ \nu i \left[k \ln \frac{w-a_2}{w-a_1} + r \ln \frac{w-a_2}{w-a_3} + \Omega(w) \right] + \frac{k+r}{w-a_2} - \frac{k}{w-a_1} - \frac{r}{w-a_3} + \Omega'(w) \right\} = 0$$

Card 2/5

8617ii

The Theory of Flow in a Channel With a Low
Triangular Hindrance at the Ground

S/140/60/000/005/001/021
C111/C222

for $\psi = q$, where $k = \frac{1-\alpha_1}{\epsilon}$, $r = \frac{1-\alpha_3}{\epsilon}$, $\nu = \frac{g}{c^3}$. ((5) follows from the Bernoulli equation for the free surface). If $F = \frac{c}{\sqrt{gh}} > 1$, then $\Omega(w)$ is sought by the arrangement

$$(12) \quad \Omega(w) = \int_0^{\infty} [A(\lambda) \exp(i\lambda w) + \bar{A}(\lambda) \exp(-i\lambda w)] d\lambda + A_0,$$

where A_0 is a real constant, $A(\lambda)$ is unknown, $\bar{A}(\lambda)$ is conjugate complex to

$A(\lambda)$. It results: $\Omega(w) = \int_0^{\infty} \frac{(\varrho + \lambda) \exp(-\lambda q)}{\lambda \theta(\lambda)} [(k+r) \cos \lambda (w-a_2) -$
 $- k \cos \lambda (w-a_1) - r \cos \lambda (w-a_3)] d\lambda$, where $\theta(\lambda) = \lambda \operatorname{ch} \lambda q - \nu \operatorname{sh} \lambda q$. If

$F < 1$, then the expression for $\Omega(w)$ is supplemented by the summands $K + B \sin \lambda_0 (w-a_2) + D \sin \lambda_0 (w-a_1) + E \sin \lambda_0 (w-a_3)$, where from (4)

Card 3/5

86174

The Theory of Flow in a Channel With a Low Triangular Hindrance at the Ground

S/140/60/000/005/001/021
C111/C222

it follows that $K = 0$, $B = - \frac{\pi(k+r)(\nu + \lambda_0) \exp(-\lambda_0 q)}{\lambda_0 \theta'(\lambda_0)}$;

$D = \frac{\pi k(\nu + \lambda_0) \exp(-\lambda_0 q)}{\lambda_0 \theta'(\lambda_0)}$, $E = \frac{\pi r(\nu + \lambda_0) \exp(-\lambda_0 q)}{\lambda_0 \theta'(\lambda_0)}$. Now the free

surface is determined with the aid of the Bernoulli equation by substituting $\frac{dz}{dw}$ into

$$(17) \quad y = h + \frac{1}{\nu} \operatorname{Re} \left(\frac{dz}{dw} - \frac{1}{c} \right),$$

and restricting to terms with ϵ in the further calculation. For the wave resistance for $F < 1$ the author finds

$$(35) \quad R = \frac{\rho c^2}{2} \cdot \frac{h_1^2}{h} f \left(\frac{h}{l_1}; \frac{h}{l_2}, F \right)$$

where f is given explicitly.
Card 4/5

86174

The Theory of Flow in a Channel With a Low
Triangular Hindrance at the Ground

S/140/60/000/005/001/021
C111/C222

The author mentions N. Kochin and K. Chadayeva. There is 1 figure and
3 references: 2 Soviet and 1 German.

ASSOCIATION: Kabardino-Balkarskiy gosudarstvennyy universitet
(Kabardino-Balkarskaya State University)

SUBMITTED: October 16, 1958

X

Card 5/5

USSR / General Problems of Pathology. Transplantation U
of Tissues and Tissue Therapy.

Abs Jour: Ref Zhur-Biol., No 11, 1958, 51576.

Author : Abdyldayev, K. A.
Inst : Kirgiz Health Dept.
Title : The Reaction of the Organism to Tissue Trans-
plants by the Method of Filatov.

Orig Pub: Sov. zdravookhr. Kirgizii, 1956, No 6, 42-46.

Abstract: Rabbit skin, preserved for a period of 6 days in
temperatures of 2-5°C, was inserted under the
skin of the concha auriculae of rabbits. Degen-
erative changes were noted already during the
first days, but no complete destruction was noted
during the course of the experiment; the reticu-
lar layer (RL) of the dermis of the graft sur-
vived. All the epithelial structures, and also

Card 1/2

COUNTRY : USSR
CATEGORY : General Biology. Individual Development.
Transplantation and Union. B
ABS. JOUR. : RZhBiol., No. 2, 1959, No. 5117
AUTHOR : Abdyldayev, K. A.
INST. : Kirghiz State Medical Institute. Homologous
TITLE : The Problem of Histological Changes of Skin
Implants.
ORIG. PUB. : Tr. Kirg. gos. med. in-ta, 1956, 8, 78-80
ABSTRACT : Pieces of rabbit skin, 4 x 4 mm in size, which
were preserved according to the method of
Filatov at a temperature of 2 - 4°C for 5 - 6
days were implanted under the skin of 52
rabbits. Within the first few days after im-
plantation degenerative changes were observed
in the epidermis and dermis of the homog-
plants. On the 4 - 8th day in some rabbits,
however, the epithelium which is situated on
the edge of the transplant preserves not only
CARD: 1/4

Country : USSR
Category :

Abs. Jour. :

Author :
Institut. :
Title :

Orig. Pub. :

Abstract : be completely keratinized in nearly all of the cases, and the upper layers of the dermis underwent necrosis. Only the mechanical layer of the dermis presented a normal appearance, which according to the author's opinion may be explained by the fact that the cells of the host penetrated into it as well as by the formation of normal, dense connective tissue. The local reaction of the host to I during the first few days was expressed by an inflammatory infiltration of the dermis at the

Card: 3/4

ABDYLDAYEV, K.A.; ARESTOVA, S.T.; MAKOVA, S.K.; ZHARKIMBAYEVA, A.Zh.

Morphogenesis of experimental hypertension under high-mountain conditions. Trudy KirgNOAGE no.2:60-62 '65.

(MIRA 18:11)

1. Iz laboratorii patomorfologii (rukovoditel' - kand.med.nauk K.A.Abdyldayev) i patofiziologii (rukovoditel' - starshiy nauchnyy sotrudnik M.A.Aliyev) Kirgizskogo instituta kray-voy meditsiny AMN SSSR. Nauchnyy konsul'tant - zasluzhennyy deyatel' nauki, prof. B.F.Malyshev.

ABDYLDAYEV, K. A. Cand Med Sci -- (diss) "Histological changes of homoimplants
in the skin of rabbits and the reaction of the hosts' organism^s to ^{them.} ~~these changes~~"
Frunze, 1957. 16 pp 22 cm. (Kirgiz State Med Inst), 120 copies. (KL, 13-57, 100)

S/179/60/000/006/019/036
E022/E107

AUTHOR: Abdyldayev, M., (Osh)

TITLE: Investigation of a Thin Film of Liquid Flowing on a Three-Dimensional Surface

PERIODICAL: Izvestiya Akademii nauk SSSR, Otdeleniye tekhnicheskikh nauk, Mekhanika i mashinostroyeniye, 1960, No. 6, pp. 120-124

TEXT: The investigation of the problem of thin liquid film on a flat plate has been described by F.I. Frankl' (Ref.1). The present article deals with a similar flow of a thin film over the surface of an ellipsoid. The author starts by introducing curvilinear coordinates x_1, x_2 , which are taken along the lines of curvature of the surface; the third coordinate $x_3 = h$ is taken along the normal to the surface. The pressure on the free surface of the liquid is assumed to be atmospheric and consequently the velocity of the flow w_0 is constant and is set equal to unity. For the limiting case when the thickness of the film tends to zero, the velocity potential of the flow is

Card 1/5

S/179/60/000/006/019/036
E022/E107

Investigation of a Thin Film of Liquid Flowing on a Three-Dimensional Surface

introduced which is then employed to express the pressure on the surface of the ellipsoid in terms of k_1 and k_2 , the two principal curvatures of the surface, and h^0 the thickness of the film (this can be deduced from the continuity equation). The flow is restricted to the bottom half of the ellipsoid, the stream of liquid approaching the ellipsoid having a constant velocity which is perpendicular to the boundary of the bowl and parallel to the tangential surfaces. Next the elliptic coordinates λ, μ, ν are introduced, λ and μ being along the lines of curvature and for the case considered $\nu = 0$. The relations between these coordinates and $x y z$ coordinates are then established and the equations for the Lamé's coefficients are developed. Since these coefficients grow indefinitely as $\lambda \rightarrow a^2$ and $\mu \rightarrow b^2$, new coordinates ξ and η called pseudo-cartesian are now introduced, which give finite values for H_λ and H_μ . By introducing differential equations of characteristics, as explained in Ref.4, it becomes apparent

Card 2/3

S/179/60/000/006/019/036
E022/E107

Investigation of a Thin Film of Liquid Flowing on a Three-Dimensional Surface

that the stream lines of the flow do not coincide with the lines of curvature, except along the central line $\lambda = a^2$. The flow along this central line is then considered at the end of the paper; the ellipsoid is assumed to have semi-axes $a^2:b^2:c^2 = 3:2:1$. The results of the analysis are tabulated. There are 1 figure, 1 table and 5 references: 4 Soviet and 1 translation from English into Russian.

SUBMITTED: May 5, 1960

Card 3/3

ABDYLDAYEV, M.

Symmetrical flow of a jet onto a solid of revolution. Uch, zap.
Osh. gos. ped. inst. no.5:87-97 '63.

Thinly laminated two-dimensional jet flow of a liquid.
Ibid.:99-107 (MIRA 18:2)

ABDYLOV, A.

Activity of the Perseid meteor stream in 1964. Izv. AN
Turk. SSR. Ser. fiz.-tekh. khim. i geol. nauk no.3:113 '65.
(MIRA 18:12)
1. Otdel geofiziki i seysmologii AN Turkmenskoy SSR.
Submitted Dec. 10, 1964.

Abdyukhanov, M.A.

"Multivibrator With Semiconductor Point-Contact Triode," by
K. S. Rzhavkin and M. A. Abdyukhanov, Radiotekhnika i Elek-
tronika, NO 12, Dec 56, pp 1478-1484

The article describes the analysis of transient processes and the method of engineering calculation of a multivibrator with one point-contact semiconductor triode, operating in the regime of self-oscillation. Oscillations close to rectangular in shape are obtained, with pulse amplitude at the collector load almost equal to the feed voltage.

Calculation is based on the principle of solving the reverse problem, i.e., with the given pulse parameters the elements of the circuit are determined. An equivalent electric circuit is worked out, which greatly simplifies the process of calculation.

*1. Fizicheskiy fakultet Moskovskogo gosudarstvennogo Universiteta
Imeni Lomonosova.
(oscillators, transistor)*

SUN.1305

ABDYUKHANOV, M.A.

109-9-9/15

AUTHORS: Kaptsov, L.N., Abdyukhanov, M.A. and Kashin, A.A.

TITLE: Application of the Quasi-Linear Method to the Analysis of a High Frequency Oscillator Employing a Transistor (Primeneniye kvazilineynogo metoda k analizu vysokochastotnogo generatora na poluprovodnikovom triode)

PERIODICAL: Radiotekhnika i Elektronika, 1957, Vol.II, Nr 9, pp. 1170 - 1173 (USSR)

ABSTRACT: A simple oscillator circuit containing a parallel RC network in the emitter and employing a single point-contact transistor (see Fig.1) is considered. The system is assumed to be operating at a comparatively high frequency so that the equivalent circuit of the transistor can be represented as an inductance L_T and a negative resistance R_T . It is assumed that under these conditions the waveform of the oscillations is sinusoidal. The circuit can easily be analysed by determining its $R_T = f_1(u_{\beta 0})|_{\omega = \text{const}}$ and its $L_T = f_2(u_{\beta 0})|_{\omega = \text{const}}$, where $u_{\beta 0}$ is the amplitude of the first harmonic of the transistor input voltage. It is more convenient, however, to replace the function L_T by a function C_T such that $C_T = 1/\omega^2 L_T$. A set of functions

Card 1/3

109-9-9/15

Application of the Quasi-Linear Method to the Analysis of a High Frequency Oscillator Employing a Transistor.

$|R_T|$ and C_T for various frequencies was determined for the Soviet point contact transistor, type CIA, operating at the emitter current of 0.1 mA and collector voltage of -20 V (see Fig.3). From these curves it is possible to determine R and C and the amplitude of the oscillations for a given frequency. It is found that C_T decreases as a function of the amplitude (of oscillations) for increasing frequencies while R_T increases with increasing amplitudes. At comparatively low frequencies R_T is practically independent of u_{co} . It was also observed that oscillations of the sinusoidal form can take place only above certain minimum frequencies, f_{min} . The values of f_{min} are of the order of 15% f_{α} , where f_{α} is the cut-off frequency of the transistor. There are 5 figures and 1 table. There is 1 Slavic reference.

Card 2/3

109-9-9/15

Application of the Quasi-Linear Method to the Analysis of a High Frequency Oscillator Employing a Transistor.

ASSOCIATION: Physics Faculty of the Moscow State University
im. M.V. Lomonosov (Fizicheskiy Fakul'tet Moskovskogo Gosudarstvennogo Universiteta im. M.V.Lomonosova).

SUBMITTED: February 20, 1957.

AVAILABLE: Library of Congress.

Card 3/3

ABDYURKHANOV, M. A.

M. A. ABRYURKHANOV: "On the limits of applicability of small signal theory for semiconducting triodes." Scientific Session Devoted to "Radio Day", May 1958, Trudrezervizdat, Moscow, 9 Sep. 58

Analysis is presented of criteria of the applicability of small signal theory, obtained by Rittner; a new formulation of the problem is given and a solution of the problem is obtained in the stationary case and for slowly varying signals.

ABDYUKHANOV, M. A.

<p>10 июня (с 18 до 22 часов)</p> <p>В. И. Савельев Тепловые режимы полупроводниковых приборов</p> <p>В. И. Витерман Исследования в расчет температурной зависимости параметров полупроводниковых транзисторов дрейфового типа</p> <p>Ю. Р. Невин, В. И. Заломин Курчатовские температурные стабилизаторы радиодетекторов на полупроводниковых транзисторах различного типа</p> <p>М. А. Абрамкин О зависимости параметров спектров полупроводниковых транзисторов от типа эмиттера</p> <p>В. И. Нелюбин Шумы в полупроводниковых усилителях</p> <p>11 июня (с 10 до 18 часов)</p>	<p>Г. И. Березинский Степенью деградации и пороговые пределы в полупроводниковых транзисторах при больших сигналах</p> <p>Т. И. Ветровица, В. И. Курьяков Исследования нелинейной работы ступенчатых схем на биполярных полупроводниковых транзисторах при частоте модуляции в зависимости от параметров транзистора</p> <p>А. Ю. Герасимов Расчет усилительного каскада на транзисторах</p> <p>В. А. Кузнецов О влиянии режима питания на полупроводниковые транзисторы на работу микросхемных схем</p> <p>11 июня (с 18 до 22 часов)</p> <p>Ю. И. Аким, В. И. Савельев, С. И. Чуриков Об устройстве схем и электрических схем в области спектров сигнала</p> <p>В. С. Рогов Влияние параметров транзистора на характеристики спектров сигнала</p>
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report submitted for the Centennial Meeting of the Scientific Technological Society of Radio Engineering and Electrical Communications in. A. S. Popov (VSEKIE), Moscow, 8-12 June, 1959

AUTHOR: Abdyukhanov, M.A. SOV/109-4-7-3/25
 TITLE: Limits of the Applicability of the Small-signal Transistor Theory

PERIODICAL: Radiotekhnika i elektronika, 1959, Vol 4, Nr 7, pp 1094 - 1102 (USSR)

ABSTRACT: The theory proposed by W. Shockley (Ref 1) is valid for small signals and is based on the assumption that the concentration of the minority carriers injected into the base of a transistor is much lower than the concentration of the majority carriers; this is written as $P/N_d \ll 1$, where P is the hole concentration and $N_d = n_o$ is the equilibrium concentration of the electrons in the base. The theory assumes the following boundary conditions for the holes in the base:

Card1/6
$$P = P_n e^{\frac{qV}{KT}} \quad (1)$$

SOV/109-4-7-3/25

Limits of the Applicability of the Small-signal Transistor Theory

where P_n is the equilibrium concentration of the holes in the base and V is the external voltage applied to the transistor. The usual continuity equation for the minority carriers in the base is expressed by Eq (2), while the hole current is given by Eq (3), where τ_p is the lifetime of the excess carriers in the base. The steady-state solution of Eq (2) is in the form of Eq (4), where W is the width of the base and L_p is the diffusion length of the holes. The hole current is given by Eq (5), where P_3 is the hole concentration at the emitter junction. E. Rittner (Ref 2) derived the following continuity equation:

Card2/6

Limits of the Applicability of the Small-signal Transistor Theory SOV/109-4-7-3/25

$$\frac{\partial P}{\partial t} = - \frac{P - P_n}{\tau_p} -$$

$$- \frac{I \frac{\partial P}{\partial x} - bqD_p N_d \left(1 + \frac{b+1}{b} \frac{P}{N_d} \right) \left(1 + 2 \frac{P}{N_d} \right) \frac{\partial^2 P}{\partial x^2} - (b-1)qD_p \left(\frac{\partial P}{\partial x} \right)^2}{qbN_d \left(1 + \frac{b+1}{b} \frac{P}{N_d} \right)^2} \quad (6)$$

and the expression for the hole current:

Card3/6

Limits of the Applicability of the Small-signal Transistor Theory ^{SOV/109-4-7-3/25}

$$I_p = \frac{PI - bqD_p(2P + N_d) \frac{\partial P}{\partial x}}{(b + 1)P + bN_d} \quad (7)$$

where $I = I_p + I_n$ is the total current in the base and $b = \mu_n/\mu_p$. These equations take into account the effect of the electric field in the base. When the ratio $P/N_d \ll 1$, Eq (6) can be simplified and written as Eq (8).

On the basis of Eq (8), Rittner (Ref 2) concluded that the small signal solution (Eqs 4 and 5) is valid when the conditions given by Eqs (9) are fulfilled. Examination of Eqs (9) shows that the applicability of Eqs (4) and (5) is restricted to very small currents (of the order of a few μA). The author is of the opinion that though the principal Rittner equations are correct, the conclusions derived from them are erroneous. Eq (6) is therefore

Card 4/6

SOV/109-4-7-3/25

Limits of the Applicability of the Small-signal Transistor Theory

analysed in some detail. The problem consists of determining the conditions such that the solutions of Eqs (2) and (6) and their derivatives with respect to x would coincide, or diverge very little. Since direct solution of Eq (6) is very difficult, the problem is tackled indirectly. It is found that for $P/N_d \ll 1$ and $(W/L_p)^2 \ll 1$, the small-signal theory which is based on Eq (2) is quite adequate. In fact, it is found that it is accurate for the emitter currents of the order of a few mA. Furthermore, it is found that the small-signal theory is valid for low-frequency signals provided $P/N_d \ll 1$, where P contains a constant as well as an alternating component. The author expresses his gratitude to V.V. Migulin, K.S. Rzhevkin, K.Ya. Senatorov and Yu.M. Az'yan for discussing this work.

Card 5/6

Limits of the Applicability of the Small-signal Transistor Theory ^{SOV/109-4-7-3/25}

There are 7 references, of which 1 is English and 6 are Soviet.

ASSOCIATION: Fizicheskiy fakul'tet Moskovskogo gosudarstvennogo universiteta im. M.V. Lomonosova (Physics Faculty of Moscow University imeni M.V. Lomonosov)

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Card 6/6

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AUTHORS: Abdyukhanov, M. A., Berestovskiy, G. N., Kuz'min, V. A.

TITLE: On the Calculation of Processes in Transistor Triodes
by the Charge Method

PERIODICAL: Radiotekhnika i elektronika, 1960, Vol 5, Nr 3, pp 450-459
(USSR)

ABSTRACT: Introduction. The usual method of calculating the electrical characteristics of semiconductor triodes is the solution of the continuity problem for the minority carriers in the emitter, base, and collector zones at certain boundary conditions, which depend on applied external voltages and currents (see W. Shokley, M. Sparkes, G. Teal, U.S. ref). Although this is the most universal method, it often leads to complicated calculations. A later method (J. Sparkes, R. Beaufoy, U.S. ref) considers the semiconductor triode as a system controlled by the charge of surplus minority carriers of the base zone. The present paper investigates the

Card 1/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959

SOV/109-5-3-13/26

relations between currents in the triode and the surplus charge carriers in the base, and analyzes the limits of the application of the charge method. Calculation examples help to evaluate its simplicity. 1. Basic relationships. The equation formulating the law of conservation of the full charge of holes in the base (p-n-p-triode) is:

$$\frac{dQ}{dt} = I_{pe} - I_{pk} - I_{VR} - I_{SR}. \quad (1)$$

where

$$Q = q \int_V (p - p_n) dV$$

is the hole charge in base of arbitrary volume V, exceeding the equilibrium charge; I_{pe} and I_{pk} are hole currents of emitter and collector, respectively; I_{VR} , I_{SR} are currents of volume and surface recombination. Further, the equilibrium hole charge will be

Card 2/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

ignored in comparison with the excess charge. Equation (1) can be derived also by integrating the continuity equation:

$$\frac{\partial p}{\partial t} = -\frac{p - p_n}{\tau_p} - \frac{\text{div } I_p}{q} \quad (2)$$

over the whole volume V of base. In order to apply (1) to practical calculations, additional conditions relating the triode (working as an amplifier) currents to the charge Q are needed. 1. Relation of collector current to charge is given by:

$$I_n = Q/\tau_n \quad (3)$$

where τ_n is coefficient depending on physical properties of the base zone of the triode. The distribution of holes in the base is linear and $\tau_n = \text{const}$. For low injection rates:

Card 3/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

$$I_n = \frac{\eta D_p p_b(0) S}{W} = \tau_n Q \frac{2D_p}{W^2},$$

where $\eta = 1 - W^2/2L_p^2$ is transfer coefficient.
Therefore,

$$\tau_n = \tau_D / \eta. \quad (3)$$

2. Concentration of holes in the base at the emitter junction is proportional to the charge Q:

$$p_b(0) = kQ. \quad (4)$$

This equation enables the determination of the relation between the charge on one side and the current of surface recombination and electron current of the emitter on the other.

$$k = \frac{2}{q\Delta W}.$$

Card 4/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

11/22
SGA/100-9-3-13/26

3. The surface recombination current I_{SR} is proportional to the hole concentration at the emitter junction:

$$I_{SR} = qsA_s p_p(0),$$

where s is surface recombination speed; A_s , effective surface area where recombination occurs. Based on (4):

$$I_{SR} = Q/\tau_s.$$

It is further assumed that $s A_s = \text{const}$, and also $\tau_s = \text{const}$. 4. The volume recombination in the base zone plays a lesser role. The lifetime of holes in volume τ_v is const for low and high injection levels, but depends on the concentration for medium injection levels. For practical purposes the lifetime in volume $\tau_v = \text{const}$ for all levels. Combining the surface and volume recombination currents; and introducing the

Card 5/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959

SOV/109-9-3-13/26

effective lifetime τ_p , the equation is written:

$$I_R = I_{VR} + I_{SR} = Q/\tau_p \quad (5)$$

where

$$\frac{1}{\tau_p} = \frac{1}{\tau_s} + \frac{1}{\tau_v}$$

5. The emitter electron current can be expressed through Q, using first the equation:

$$I_{ne} = \frac{qD_n S}{L_n} n_e(0) \text{ or } I_{ne} = \frac{qD_n S}{L_n} \frac{n_b(0)p_b(0)}{p_e(0)} \quad (6)$$

Since $p_e(0) = p_p$ is equilibrium concentration of holes in the emitter, $n_b(0) = n_{II} - p_{II} + p_b(0)$ as corresponding to the neutrality condition in each point of the base and $p_b(0) = kQ$, Eq. (6) takes shape:

Card 6/21

On the Calculation of Parameters in Triodes by the Charge Method

11
 207/2001-3-13/0

$$I_{n2} = a_1 Q + a_2 Q^2 \tag{7}$$

where a_1 and a_2 are constant coefficients. Substituting the above expressions for (1), and taking into consideration that $I_{pe} = I_c - I_{ne}$; $I_{pk} = I_k$; $I_b = I_c - I_k$, the equations, which together with conditions (1) and (5) constitute the whole set needed for calculations per charge method, are derived:

$$\frac{dQ}{dt} + \frac{Q}{\tau_p} + a_1 Q + a_2 Q^2 = I_b \tag{8}$$

or

$$\tau_n \frac{dI_n}{dt} + \left(\frac{\tau_n}{\tau_p} + a_1 \tau_n \right) I_n + a_2 \tau_n^2 I_n^2 = I_b \tag{9}$$

Card 7/21

On the Calculation of Processes in Transistor Triodes by the Charge Method

77959
SOV/109-2-3-13/20

$$\tau_n \frac{dI_n}{dt} + \left(1 + \frac{\tau_n}{\tau_p} + a_1 \tau_n\right) I_n + a_2 \tau_n^2 I_n^2 = I_e \quad (10)$$

These conditions are valid as long as charge Q varies with sufficient slowness in comparison to the diffusion time τ_D . If the charge varies with the time constant $\tau \approx \tau_D$, the charge method can give considerable error. In some cases, however, the method can still be used as an approximation for some fast processes. As an example, the transient characteristic of a triode with a common base for small signals is investigated. The emitter current suddenly changes from 0 to I_{e0} at some $t = 0$. $I_k(t)$ is sought. For simplicity the emitter current I_{ne} is ignored. Eq. (10) takes shape:

Card 8/ 21

$$\tau_n \frac{dI_n}{dt} + I_n = \tau_n I_{e0}$$

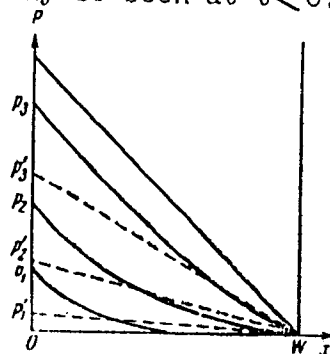
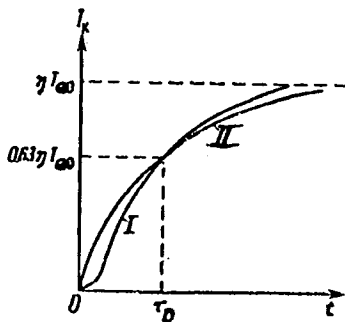
On the Calculation of Processes in Triode
Triodes by the Charge Method

77939
SOV/109-5-3-13/26

Its solution is:

$$I_k(t) = \eta I_{\infty} [1 - \exp(-t/\tau_D)] \tag{11}$$

which is very often used for practical applications. Figure 2 shows the exact transient characteristic I and the approximated II as calculated per (11), where a pronounced difference may be seen at $t < 0.2 \tau_D$.



Card 9/21

Fig. 2

Fig. 3

See caption to both figures on Card 10/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

Fig. 2. Transient characteristics of transistor triode in a circuit with a common base: (I) exact curve; (II) calculated per (11).

Fig. 3. Hole concentration in the emitter base at different times: (p_1, p_2, p_3) actual values: (p_1', p_2', p_3') calculated per (4).

This investigated example proves that for many practical cases relation (3) is valid and sufficiently accurate; the same is true when the base charge varies with the time constant $\tau \approx \tau_D$. Figure 3 shows the distribution of holes in the base at different moments; since the calculated values (per 4) are lower than the actual, the I_{SR} and I_{ne} are also smaller than the actual magnitudes. But the influence of the recombination current and electron current

Card 10/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

of the emitter are important only for circuits where the charge at the base varies with the time constant, considerably exceeding τ_p ; hence Eqs. (5) and (7) can be considered valid. Equation (1) expressing the law of charge conservation is valid for any geometry of the base. But since Eqs. (1)-(5) were proved only by solution of the continuity equation for a one-dimensional case, the field of application of the method is proved only for a one-dimensional model of transistor-triodes. 2. On the influence of the emitter electron current on the transient characteristic of the transit triode, connected with a common emitter. The influence of the injection coefficient on the transient characteristic of the triode was investigated by E. I. Adirovich and K. V. Temko (USSR). In this work within the frame of theory of a small signal and assuming $\gamma = \text{const}$ during the transient process, the diffusion equation for holes of the base was solved, but giving a cumbersome result, approximated by the following equation:

Card 11/21

On the Calculation of Processes in Transistor
 Triodes by the Charge Method

779/9
 SOV/109-5-3-13/26

$$i_A(t) = \frac{I_{B0} \cos \gamma}{1 + \gamma^2} \left[1 - \exp \left\{ - \left[\frac{1}{\tau_p} + \frac{(\sin \cos \gamma)^2}{\tau_p} \right] t \right\} \right] \quad (12)$$

The transient characteristic for the transistor-triode is now calculated for moment $t = 0$ at which the base current jumps from 0 to I_{B0} . For a small signal in (7) the second term can be ignored, and Eq. (9) can be written as:

$$\text{where } \frac{di_n}{dt} + \frac{i_n}{\tau} = \frac{I_{B0}}{\tau_n} \quad (13)$$

$$\frac{1}{\tau} = \frac{1}{\tau_p} + \frac{1}{\tau_r}, \quad \tau_2 = \frac{1}{\alpha_1} \quad (14)$$

Card 12/21

From the steady distribution of holes in the base,

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959

SOV/109-5-3-13/26

τ_e can be determined:

$$\tau_e = \frac{\tau_D}{1-\gamma}. \quad (15)$$

The solution of (13) is:

$$I_n(t) = \frac{\eta\tau^*}{\tau_D} I_{b0} [1 - \exp(-t/\tau)]. \quad (16)$$

Taking (15) into consideration and using the equation

$\tau_D = \tau_p(1-\eta)$, we get:

$$I_n(t) = \frac{\alpha}{1-\alpha} I_{b0} \left\{ 1 - \exp \left[- \left(\frac{1}{\tau_p} + \frac{1-\gamma}{\tau_D} \right) t \right] \right\} \quad (17)$$

or

Card 13/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959

SOV/109-5-3-13/26

$$I_n(t) = \frac{\alpha}{1-\alpha} I_{b0} \left\{ 1 - \exp \left[-\frac{(1-\alpha)t}{\tau_D} \right] \right\} \quad (18)$$

(the authors refer here to J. Sparkes, R. Neaufoy, U.S. ref). From these expressions it follows that the collector current varies with the time constant $\tau^* < \tau_p$, where the inequality increases with decrease of γ and τ_D . The influence of the electron current on the transient characteristic can be ignored when $\tau_e / \tau_p \geq 10$ or:

$$\frac{\tau(1-\eta)}{1-\gamma} \geq 10. \quad (19)$$

Usually $\eta = 0.98$ and (19) is satisfied when $\gamma \geq 0.998$. For values γ close to one the index of the exponential of formula (12) is:

Card 14/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77000
SOV/109-5-3-13/26

$$\frac{1}{\tau_p} + \frac{(\arccos \gamma)^2}{2\tau_D} \approx \frac{1}{\tau_p} + \frac{1-\gamma}{\tau_D}$$

which is close to the one given in Eq. (17). 3. Calculation of the current amplification coefficient and output conductance of the transistor triode with consideration of the modulation of the base zone thickness. A harmonically varying current with an amplitude small as compared with the amplitude of the emitter bias current, is applied at the input of the transistor triode with a grounded base. Limiting calculations to low injection levels, the modulation of the base thickness is considered. All variables depending on time are assumed to vary harmonically, and to be small in magnitude as compared with variables corresponding to a steady state. The equation of conservation of charge:

Cont 15/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959

SOV/109-5-3-13/26

$$\frac{dQ}{dt} = -\frac{Q}{\tau_p} + I_{pk} - I_n \quad (20)$$

will be solved. For emitter current:

$$I_k = I_{k0} + i_{k0} \exp j\omega t,$$

for collector current:

$$I_n = I_{n0} + i_{n0} \exp j\omega t$$

for collector voltage:

$$V_n = E_n + v_{n0} \exp j\omega t,$$

where i_{k0} and v_{k0} are complex amplitudes. After
respective substitutions the complex amplitude is
calculated from (20) as:

ed 10/21

On the Calculation of Processes in Triode
 Triodes by the Charge Method

77959
 SOV/109-5-3-13/26

$$i_{n0} = \alpha i_{s0} + G_k v_{n0} \tag{23}$$

where

$$\alpha = \frac{\gamma_0}{1 + \frac{\tau_n}{\tau_p} + j\omega\tau_n} = \frac{\alpha_0}{1 + j\omega\tau_D} \tag{24}$$

is the amplification coefficient per current for shortcircuited output given as approximation valid up to the critical frequency and

$$G_k = \frac{\gamma_0}{1 + j\omega\tau_D} \left[-\frac{1}{\tau_p} \frac{\partial \tau_n}{\partial V} I_{s0} + \frac{\partial \gamma_0}{\partial V} I_{s0} - j\omega \frac{\partial \tau_n}{\partial V} I_{s0} \right] \frac{\partial V}{\partial V_n} \tag{25}$$

the output conductance, dependent on the modulation of the thickness of the base zone. Separating the active and reactive part of G_k for the one-dimensional

Card 17/21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

model of the triode:

$$g_n = \frac{g_0 + \omega^2 \tau_D^2 C_0}{1 + \omega^2 \tau_D^2}, \quad C_{gn} \approx \frac{C_0}{1 + \omega^2 \tau_D^2}, \quad (26)$$

where g_0 and C_0 are values of the active part of the output conductance and diffusion capacity at low frequencies, determined by:

$$g_0 = \frac{\partial(\tau_D \gamma_D)}{\partial W} \frac{\partial W}{\partial V_n} I_{E0}, \quad (27)$$

$$C_0 = -\tau_D \frac{W_0}{D_p} \frac{\partial W}{\partial V_n} I_{E0}, \quad (28)$$

which coincide with the exact expressions derived from solution of the diffusion equation by J. M. Early (U.S. ref). The expressions for output conductivity are valid up to the critical frequency. If the variable

Card 18/ 21

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

voltage on the collector is caused by a load at the
output $v_{ko} = -i_{ko} R_l$, it follows from (23) that:

$$i_{no} = \frac{\alpha}{1 + R_l G_n} \quad (29)$$

which shows that with increase of the load resistance
the amplification coefficient per current drops.
Figure 4 shows comprehensively the change of collector
voltage with thickness of base.

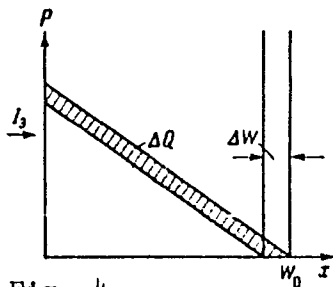


Fig. 4. Dependence of the
charge Q on the thickness of
the base zone W at constant
emitter current.

Card 19/21

Fig. 4.

On the Calculation of Processes in Transistor
Triodes by the Charge Method

77959
SOV/109-5-3-13/26

Conclusions. The charge method being convenient for engineering calculations of problems of transistor triode electronics is as valid for slow processes as the known methods based on solution of continuity equations. For many instances it is valid also for processes with time constants close to the critical frequency. It is possible that this method, after some modifications, could be applied to calculations of problems not only of fused, but also of drift transistor triodes. There are 4 figures; and 21 references, 8 Soviet, 11 U.S., 2 Japanese. The most recent or referred to U.S. references are: W. Shockley, M. Sparkes, G. Teal, P-N Transistor, Phys. Rev., 83, 7, 151 (1951); J. Sparkes, R. Beufoy, The Junction Transistor as a Charge Controlled Device, Proc. I.R.E., 45, 12, 1740 (1957); F. G. Hyde, Some Measurements of Commercial Transistors and Their Relation to Theory, Proc. I.R.E., p. B. 105, 19, 45 (1958); L. D. Armstrong, C. L. Carlson, M. Bentivedna, P-N-P Transistor Using High-Emitter-Efficiency Alloy

Card 20/21

On the Calculation of Processes in Transistor
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77959
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Card 21/21

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SOV/109-5-3-16/26

AUTHOR: Abdyukhanov, M. A.

TITLE: Change in Critical Frequency and Output Conductance of Fused Semiconductor Triodes With the Emitter Current

PERIODICAL: Radiotekhnika i elektronika, 1960, Vol 5, Nr 3, pp 478-489 (USSR)

ABSTRACT: One of the important characteristics of semiconductor triodes is the current amplification α in a circuit with common base and shortcircuited. Amplitude, phase, frequency characteristics of α determine to a great extent the frequency characteristics of transistor triodes. It was found that the usual range of emitter current consists of three zones. The zone of low positive shift of the emitter has a low α_0 value due to a recombination in the p-n junction. In the second zone of medium injection levels, the role of recombination is smaller and α_0 is higher. Finally, in the

Card 1/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962

SOV/109-5-3-16/26

third zone a higher emitter current lowers the injection coefficient and consequently α_0 . A study of frequency properties of α shows the same picture. At low injection levels frequency properties of α are determined by the diffusion of holes in the base area. The critical frequency depends on the width W of base area and on the diffusion coefficient D_p .

$$f_c = \frac{2.43D_p}{2\pi W^2} \quad (1)$$

Tests undertaken by the author did show that at low levels of injection the critical frequency is not constant but increases with an increasing emitter current. This rise is fast at low level of current; slows down at medium injection levels; reaches a maximum value and tapers off at a further rise of current. Previous attempts to explain this decrease failed, and the present article tries to find the reasons for it. Besides this it is necessary to clarify the relation of output conductance of the transistor

Card 2 / 2 2

Change in Critical Frequency and Output
 Conductance of Pused Semiconductor
 Triodes With the Emitter Current

1979
 SOV/109-5-5-16/26

triode with grounded base to the emitter current, which for high injection levels has characteristics different from low injection levels. This paper is further concerned with the calculation of output conductance for large signals by the charge method, and experimental investigation of its dependence on the emitter current. (1) Dependence of Critical Frequency on Emitter Current at Low Injection Levels: Under these conditions, the static capacitance C_e of the p-n junction influences the critical frequency, considerably lowering ω at high frequencies. Capacitance C_e is connected in parallel with the input diffusion conductance of the triode, the expression for the latter being:

$$G_{in} = \frac{q}{kT} \frac{S_e D_p p_n e^{qV_e/kT}}{L_p} \sqrt{1 + j\omega\tau_p} \coth \left[\sqrt{1 + j\omega\tau_p} \frac{W}{L_p} \right], \quad (2)$$

Card 3/22

where $L_p = \sqrt{D_p \tau_p}$ is the so-called diffusion

Change in Critical Frequency and Output
 Conductance of Fused Semiconductor
 Triodes With the Emitter Current

77962
 SOV/109-5-3-16/26

length for base holes; p_n is the balanced concentration of holes in the base. The input alternating current i_e consists of the bias current $i_b = j(\omega) C_e v_e$, hole diffusion current $i_{pe} = G_{in} v_e$, and emitter electron current $i_{ne} = (1 - \gamma_o) / \gamma_o i_{pe}$; $i_e = i_b + 1/\gamma_o i_{pe}$.

The output current is $i_k = \eta i_{pe}$, where η is coefficient of hole transfer from emitter to collector. Therefore, the current amplification coefficient is

$$\alpha' = \alpha(j\omega) \frac{G_{in}}{G_{in} + j\omega C_e \gamma_o} \quad (3)$$

where $\alpha(j\omega)$ is the "inner" current amplification coefficient. Using the simple approximation for

$$\coth \left[\sqrt{1 + j\omega \tau_p} \frac{W}{L_p} \right] \text{ and the expression which is valid up}$$

Card 4/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77902
SOV/109-5-3-16/26

to the critical frequency:

$$\alpha(j\omega) = \frac{\alpha_0}{1 + j \frac{\omega}{\omega_\alpha}}, \quad (4)$$

where ω_α can be found from (1), the expression sought is:

$$\alpha' = \frac{\alpha_0}{1 + j \frac{\omega}{\omega_\alpha}}, \quad (5)$$

where

$$\omega_\alpha = \omega_\alpha \frac{1}{1 + \omega_\alpha (r_e r_n \tau_0)}, \quad (6)$$

but $r_e = kT/qI_e$. From here on, apostrophes indicate measured variables. More exact approximations do not

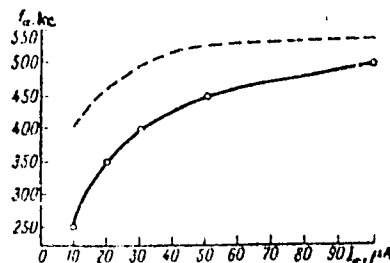
Card 5/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

have practical values.

Fig. 1: Critical frequency
versus emitter current at
low currents for triode
type П1 B (PlV).



The solid curve of Fig. 1 shows experimental results, the dotted, those theoretically computed from (6).
(2) Electronic Peculiarities of Semiconductor Triodes at Medium and High Injection Levels, and Factors Lowering the Critical Frequency: Two features lead to

Card 6/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

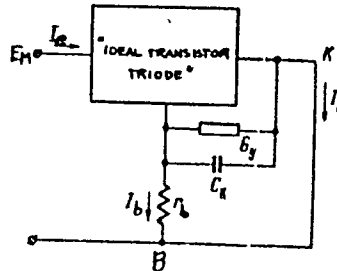
a drop of critical frequency when the injection level reaches $p_e/n_0 \approx 5$ to 7: (a) There is, in the base area, a large charge of surplus holes and the modulation of base volume results in a high conductance parallel to the junction and proportional to emitter current. This leads to a decrease of critical frequency. (b) A considerable radial field is formed across the basic path of hole movement, which causes a drop of potential between the base and the emitter junction; therefore, the height of potential barrier at the junction declines at the edges of the emitter; and the concentration of injected holes at these edges increases as compared with the concentration at the center. Each of these peculiarities is discussed further below. (3) Influence of Base Resistance on Critical Frequency at High Emitter Currents: The triode shown on Fig. 2 is assumed to be ideal, and to it resistance r_b is connected as an outside element. For medium and high injection levels

Card 7/22

Change in Critical Frequency and Output
 Conductance of Fused Semiconductor
 Triodes With the Emitter Current

77962
 SOV/109-5-3-16/26

Fig. 2. Equivalent circuit
 of semiconductor triode
 with r_b , C_k , and G_y .



the continuity equation of hole concentration is non-linear and solution of the problem with the same precision as for low injection levels is not possible; therefore, the charge method will be used to determine the current amplification. Instead of a continuity equation an equation of charge conservation of surplus holes in the base area is solved:

Card 8/22

Change in Critical Frequency and Output
 Conductance of Fused Semiconductor
 Triodes With the Emitter Current

77962
 SOV/109-5-3-16/26

$$\frac{dQ}{dt} = -\frac{Q}{\tau_p} + I_{pe} - I_n \quad (7)$$

with the relation of charge Q to collector current per:

$$I_n = \frac{Q}{\tau_n} \quad (8)$$

where $Q = q \int_V (p - p_n) dv$; V is the base volume; $\tau_K = \tau_D / \eta_0$;

τ_D is diffusion time of holes from emitter to collector.
 The solution of (7) using (8) results in:

$$i_{in} = \tau_0 \eta_{ew} + G_n v_{in} \quad (9)$$

WHERE

$$G_n = \frac{\eta}{\eta_0} (G_0 + j\omega C_0) + G_y + j\omega C_n \quad (10)$$

$$G_0 = \frac{1}{\tau_p} \frac{\partial Q_0}{\partial V_n} + I_{ew} \frac{\partial \tau}{\partial V_n} \quad (11)$$

Card 9/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

$$C_o = \frac{\partial G_o}{\partial V_k}; \quad (12)$$

G_o and C_o are low-frequency values of active part of output diffusion conductance and diffusion capacitance:

$$\eta = \frac{\eta_o}{1 + j\omega r_o} \quad (13)$$

is the transfer coefficient; G_y is conductance of collector leakage; C_k is static capacitance of collector; i_{eo} , i_{ko} , and v_{ko} are complex amplitudes of variable components of emitter and collector currents and collector voltage. In the absence of load $v_{ko} = (i_{eo} - i_{ko})r_b$ and substituting this expression into (9), the coefficient of current transmission is obtained:

$$\alpha' = \frac{\alpha + G_y r_b}{1 + G_y r_b} \quad (14)$$

Card 10/22

Change In Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

7752
SOV/109-5-5-16/26

which is identical at low injection levels with the equation of hole density diffusion. A calculation of G_0 and C_0 , per (11) and (13), using (8), leads to the active part G and diffusion capacitance C :

$$G = \frac{G_0 + \frac{\omega^2}{\omega_a^2} C_0}{1 + \frac{\omega^2}{\omega_a^2}} \quad (15)$$

$$C = \frac{C_0}{1 + \frac{\omega^2}{\omega_a^2}} \quad (16)$$

This coincides with high-frequency approximations of output conductance derived by Yu. A. Kamenetskiy from exact expressions of output conductance:

$$G_{kp} = \frac{\alpha_0}{I_p} \frac{\partial W}{\partial V_K} I_{e0} \sqrt{1 + j\omega\tau_p} \operatorname{th} \left[\sqrt{1 + j\omega\tau_p} \frac{W}{L_u} \right] \quad (17)$$

Card 11/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

For medium and high injection levels, G and C can be calculated per (15) and (16) with the respective

ω_α , G_0 , and C_0 determined by experiments. Figure 3 (a,b) shows experimental data on relation of G_0 and C_0 to emitter current of Π_1 , Π_6 , and Π_{15} triodes.

Assuming in (14) $|\alpha'| = \alpha_0 / \sqrt{2}$ the following expression for critical frequency is obtained:

$$f_c = f_a \frac{1}{\sqrt{1 + 2b_0 + \frac{4b_1}{\alpha_0}}}, \quad (18)$$

where $b_0 = 2\pi f_a C_0 r_b$, $b_1 = 2\pi f_a C_1 r_b$. As C_0 increases in proportion

to emitter current, while r_b is independent of same (Fig. 4), critical frequency decreases when I_e rises per (18). In order to verify expression (18) the

Card 12/22

Change in Critical Frequency and Output
 Conductance of Pused Semiconductor
 Triodes With the Emitter Current

77962
 SOV/109-5-3-16/26

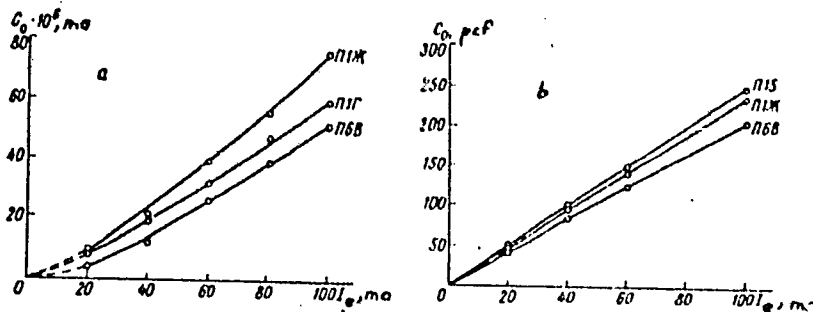


Fig. 3. Active portion of output conductance (a) and diffusion capacitance of collector (b) versus emitter current.

Card 13/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

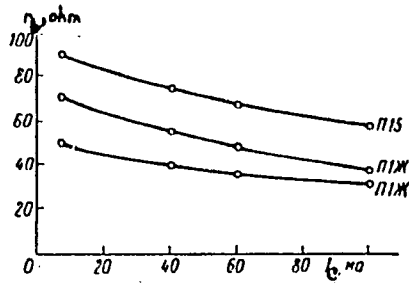


Fig. 4. Base resistance versus emitter current.

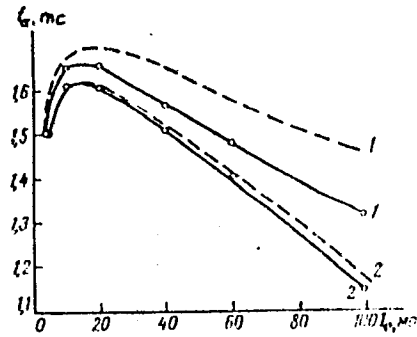


Fig. 5. Critical frequency versus high emitter current.

Card 14/22

Change in Critical Frequency and Output
 Conductance of Fused Semiconductor
 Triodes With the Emitter Current

7792
 SOV/109-5-3-16/26

dependence of critical frequency on emitter current was measured (Fig. 5, solid curve 2). An additional resistance $R_b = 50 \text{ cm}$ was imposed, in this case in the base line. Dashed line 2 shows the same dependence when a resistance $(R_b + r_b)$ was imposed and for f_{α} values determined from dashed curve 1. Solid line 1 shows the same dependence for $\Pi 1\mathbb{K}$ triode, while dashed line 1 shows the effect of excluded influence r_b per (18). (4) Influence of the Radial Field on Critical Frequency: Actual triode emitters and collectors have spherical rather than planar surfaces (see Fig. 6). A mathematical solution for these surfaces presents insurmountable difficulties, and a simple method for determining the average base width W consists in the calculation of time constant $T = r_e C_{de}$ which determines the frequency properties of α up to critical frequency. Here r_e is input resistance of triode (disregarding r_b),

Card 15/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962

SOV/109-5-3-16/26

$C_{de} = \partial Q / \partial V_e$ is input diffusion capacitance.
Assuming the surfaces spherical and hole distribution
to be linear, for $R_1^2 \gg r_1^2$ where $r_1 = d_1/2$,

$$\tau = \frac{W_0^2}{2D_p} \left(1 + \frac{kr_1^2}{2W_0} \right)^2 \quad (20)$$

where W_0 (shown on Fig. 6) is the shortest distance
between junctions. From (20) it follows that:

$$\bar{W} = W_0 \left(1 + \frac{kr_1^2}{2W_0} \right) \quad (21)$$

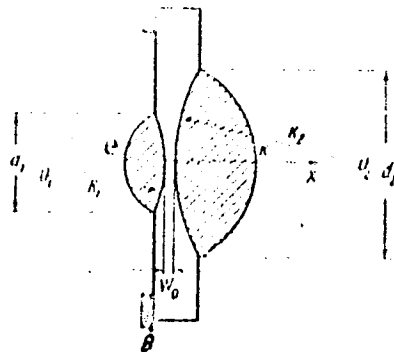
The presence of unequal distribution of injected
holes along the emitter junction causes increase of
 \bar{W} for large emitter currents. In order to determine
the distribution of concentration of injected car-
riers in the base along radius r and to calculate \bar{W} ,

Card 16/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

7(902)
SOV/109-5-3-16/26

Fig. 6. Schematic
representation of a
fused triode in cross
section



the voltage drop at the base $V(r)$ must be
calculated first. This is done under following
assumptions: (1) The volume recombination of excess
in the base is ignored; (2) The emitter surface is
considered equipotential since the emitter material

Card 17/22

Change in Critical Frequency and Output
 Conductance of Fused Semiconductor
 Triodes With the Emitter Current

77962
 SOV/109-5-3-16/26

conductance is high compared with the base conductance; (3) The distribution of holes and electrons in the base along direction x is linear; (4) The distribution of the electron current in the base zone can be determined from $\partial j_{nx} / \partial x = A \sigma(x)$ where $\sigma(x) = \sigma_0 \left[1 + \frac{p_0}{n_0} \left(1 - \frac{x}{W(r)} \right) \right]$ constant conductivity A at point. Under these assumptions the equation for $V(r)$:

$$V(r) = \int_r^{r_1} \rho(\xi) j_{nr}(0, \xi) d\xi,$$

where $\rho(r)$ is specific conductivity at base along emitter surface, is transformed into:

$$V(r) = \frac{U_{pb}}{W_0} \int_r^{r_1} \frac{dz}{1 + \frac{p_0(z)}{n_0}} \int_0^z \frac{p(\xi)}{n_0} \left[1 + \frac{p(\xi)}{n_0} \right] \frac{\xi d\xi}{\left[1 + \frac{p(\xi)}{2n_0} \right] \left(1 + \frac{p(\xi)}{W_0} \right)}. \quad (24)$$

Card 18/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

7790E
SOV/109-5-3-16/26

This equation can only be approximately solved:

$$V(r) = \frac{kT}{q} a \ln \left[\frac{1 + \frac{gr^2}{2W_0}}{1 + \frac{kr^2}{2W_0}} \right], \quad (25)$$

where

$$a = \frac{q}{kT} B \rho_0 \frac{I_e}{n_0} \frac{1}{g}. \quad (26)$$

The distribution of injected hole concentration can be determined using equation

$$p_e(r) = p_e(r_0) \left[\frac{1 + \frac{gr^2}{2W_0}}{1 + \frac{kr^2}{2W_0}} \right]^a. \quad (27)$$

The time constant can be evaluated for $a = 1, 2, 3, 4, \dots$.
The author concludes that while a linear distribution of holes along x-axis was assumed by the theory, the

Card 19/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

influence of a radial field bends their path from emitter to collector leading to their increased charges in the base and \bar{W} . The nonuniform distribution of holes on the emitter surface leads to a relative increase of the surface recombination current, which must be considered for determination of the current amplification at large emitter currents. Conclusions: The experimental data and theoretical calculations presented prove that the increase of the critical frequency with emitter current for low currents is basically determined by the weakening of the shunting influence of the static capacitance of the p-n junction. For medium and large injection levels, the experiments show not doubling (as should be expected from theoretical considerations), but only 40-50% increase as compared with the critical frequency for injection level $p_e/n = 0.1$.

Card 20/22

The presence of a radial electrical field in the base, and base resistance, cause a drop of the critical

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

frequency at large emitter currents. Experiments and theoretical calculations of output conductance at large emitter currents did show it has mostly a diffusion character and increases in proportion to the emitter current. K. Rzhevkin assisted in this work. There are 6 figures; and 16 references, 4 Soviet, 8 U.S., 2 U.K., 2 Japanese. The most recent U.S. references are: Chih-Tang Sah, R. N. Noyce, W. Shockley, Current Generation and Recombination in P-N Junctions and P-N Junction Characteristics, Proc. IRE, 1957, 45, 9, 1228; W. Gaertner, R. Hanel, R. Stampel, F. Caruso, The Current Amplification of a Junction Transistor as a Function of Emitter Current and Junction Temperature, Proc. IRE, 1958, 46, 11, 875; M. I. Meyer, On the Variation of Transistor Small-Signal Parameters With Emitter Current and Collector Voltage, J. Electronics and Control, 1958, 4, 4, 305; M. I. Meyer, Supplementary Note to the Paper: On the Variation of Transistor Small-Signal Parameters With Emitter Current and Collector Voltage, 1958, 5, 4, 329; N. H. Fletcher,

Card 21/22

Change in Critical Frequency and Output
Conductance of Fused Semiconductor
Triodes With the Emitter Current

77962
SOV/109-5-3-16/26

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1669.

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Card 22 / 22